

30 Volt P-Channel PowerTrench[®] MOSFET

General Description

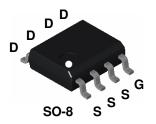
This P-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers, and battery chargers.

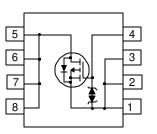
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS}(\text{ON})}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- -13 A, -30 V. $R_{DS(ON)} = 9 \ m\Omega \ @V_{GS} = -10 \ V$ $R_{DS(ON)} = 13 \ m\Omega \ @V_{GS} = -4.5 \ V$
- Extended $V_{\mbox{\scriptsize GSS}}$ range (–25V) for battery applications
- ESD protection diode (note 3)
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage		-25/+20	V
D	Drain Current – Continuous	(Note 1a)	-13	A
	- Pulsed		-50	
PD	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1.0	
T_J, T_{STG}	Operating and Storage Junction Temperation	ure Range	–55 to +175	C°
Therma	I Characteristics			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6679Z	FDS6679Z	13"	12mm	2500 units

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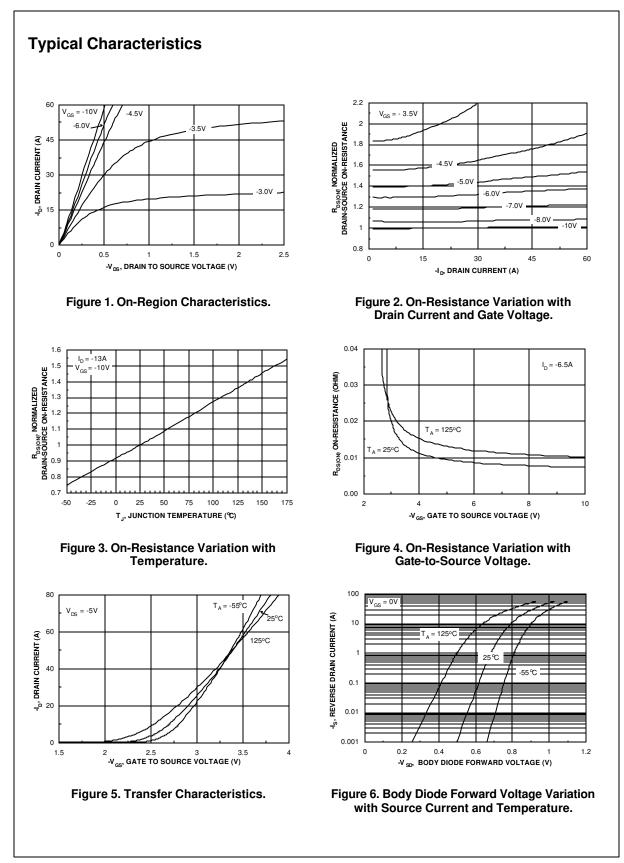
△BV DSS Bread △T」 Coer bss Zerd ksssF Gate kssR Gate On Characte V _{GS(th)}	ristics n–Source Breakdown Voltage akdown Voltage Temperature fficient o Gate Voltage Drain Current e–Body Leakage, Forward	$V_{GS} = 0 V$, $I_D = -250 \mu A$ $I_D = -250 \mu A$, Referenced to 25°C $V_{DS} = -24 V$, $V_{GS} = 0 V$	-30		[V
BV _{DSS} Drai ΔBV _{DSS} Bread ΔTJ Coe bss Zerro IgssF Gate IgssR Gate VGS(th) Gate	n–Source Breakdown Voltage akdown Voltage Temperature fficient o Gate Voltage Drain Current	$l_{\rm D}$ = -250 µA,Referenced to 25°C	-30			V
∆BVDSs △TJ Bread Coer bss Zerd ksssF Gate kssR Gate On Characte VGS(th)	akdown Voltage Temperature fficient o Gate Voltage Drain Current	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^\circ\text{C}$				
IGSSF Gate IGSSR Gate On Characte VGS(th)		$V_{22} = 24 V V_{22} = 0 V$		-22		mV/°C
I _{GSSR} Gate On Characte V _{GS(th)} Gate	e-Body Leakage, Forward	$\mathbf{v}_{\mathrm{DS}} = -24 \mathbf{v}, \mathbf{v}_{\mathrm{GS}} = \mathbf{U} \mathbf{v}$			-1	μA
On Characte		$V_{GS} = -25 V, V_{DS} = 0 V$			-10	μA
V _{GS(th)} Gate	e–Body Leakage, Reverse	$V_{GS}=20\ V, V_{DS}=0\ V$			10	μA
V _{GS(th)} Gate	ristics (Note 2)	· · · ·				
()	e Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-1	-1.7	-3	V
	e Threshold Voltage	$l_D = -250 \ \mu$ A,Referenced to 25°C		4.9		mV/ºC
R _{DS(on)} Stat	ic Drain–Source	$V_{GS} = -10 \text{ V}, I_D = -13 \text{ A}$		7.2	9	mΩ
On-	On-Resistance	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -11 \text{ A}$		10	13	
	Otata Duain Ourseat	V_{GS} =-4.5 V, I_D =-13A, T_J =125°C V_{GS} = -4.5 V, V_{DS} = -5 V	50	10	13	•
- (*)	State Drain Current	$V_{GS} = -4.5 V, V_{DS} = -5 V$ $V_{DS} = -5 V, I_D = -13 A$	-50	40		A
0.0	ward Transconductance	$v_{DS} = -3 v$, $v_D = -13 A$		43		S
Dynamic Cha						
-	t Capacitance	$V_{DS} = -15 V, V_{GS} = 0 V,$		3803	ļ	pF
	out Capacitance	f = 1.0 MHz		974	ļ	pF
C _{rss} Rev	erse Transfer Capacitance			490		pF
Switching Cl	naracteristics (Note 2)					-
- (-)	n–On Delay Time	$V_{DD} = -15 V, I_D = -1 A,$		18	32	ns
	n–On Rise Time	$V_{GS} = -10 \text{ V}, \ R_{GEN} = 6 \Omega$		9	18	ns
- (-)	n–Off Delay Time	_		92	147	ns
-	n–Off Fall Time			54	86	ns
*	al Gate Charge	$V_{DS} = -15 V, I_D = -13 A,$ $V_{GS} = -10 V$		67	94	nC
0	e-Source Charge	$v_{GS} = -10$ v		11	<u> </u>	nC
Q _{gd} Gate	e-Drain Charge			15		nC
Drain–Sourc	e Diode Characteristics a	and Maximum Ratings				-
ls Max	imum Continuous Drain–Source I	Diode Forward Current			-2.1	A
V _{SD} Drai Volt	n–Source Diode Forward age	$V_{GS} = 0 \ V, I_S = -2.1 \ A (Note 2)$		-0.7	-1.2	V

Scale 1 : 1 on letter size paper

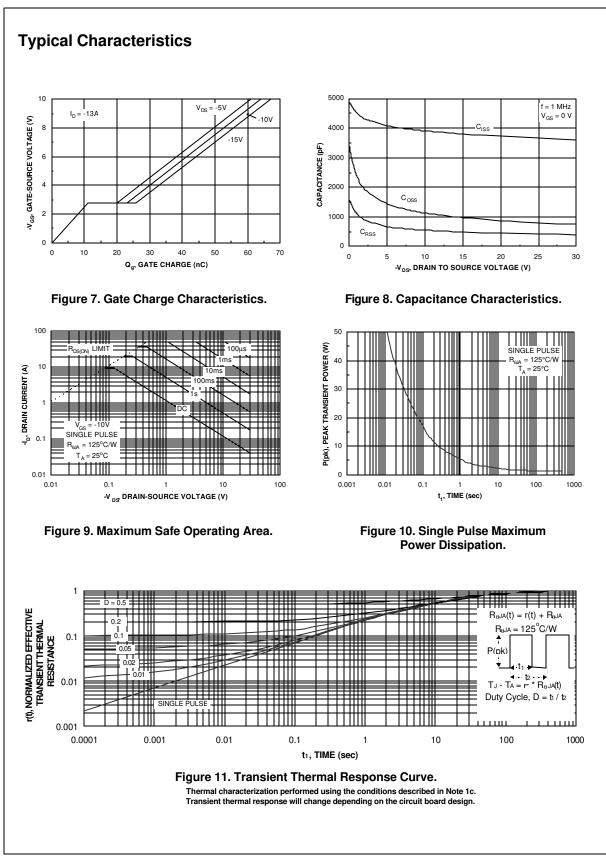
2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty Cycle < 2.0%

3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

FDS6679Z Rev C(W)



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